

(2019.11.01 Revised)

Comparison Evaluation of Power Inductors

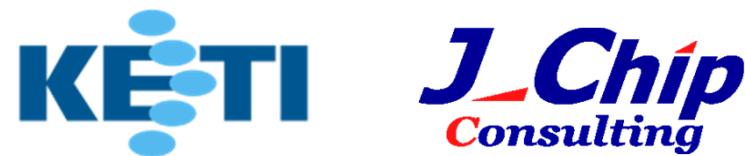


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V. Environmental tests

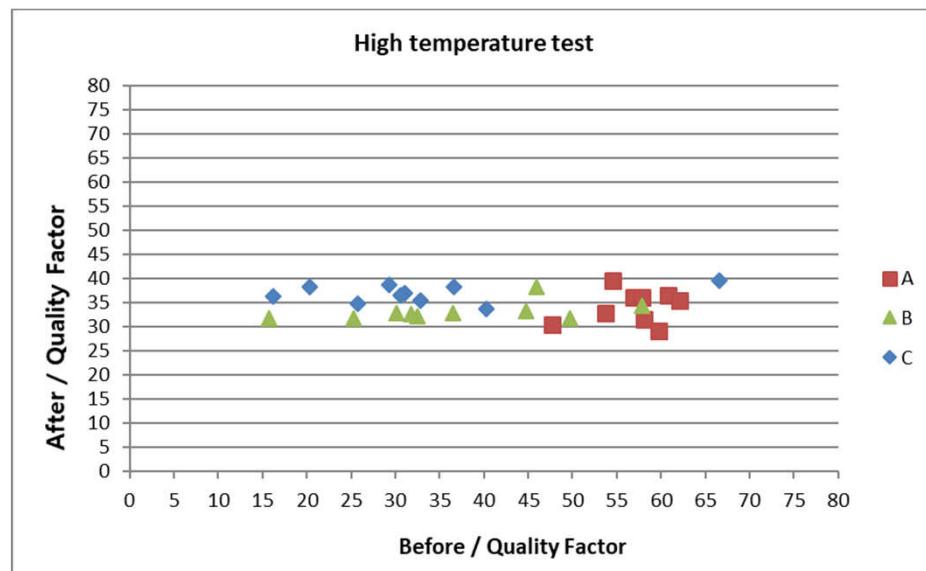
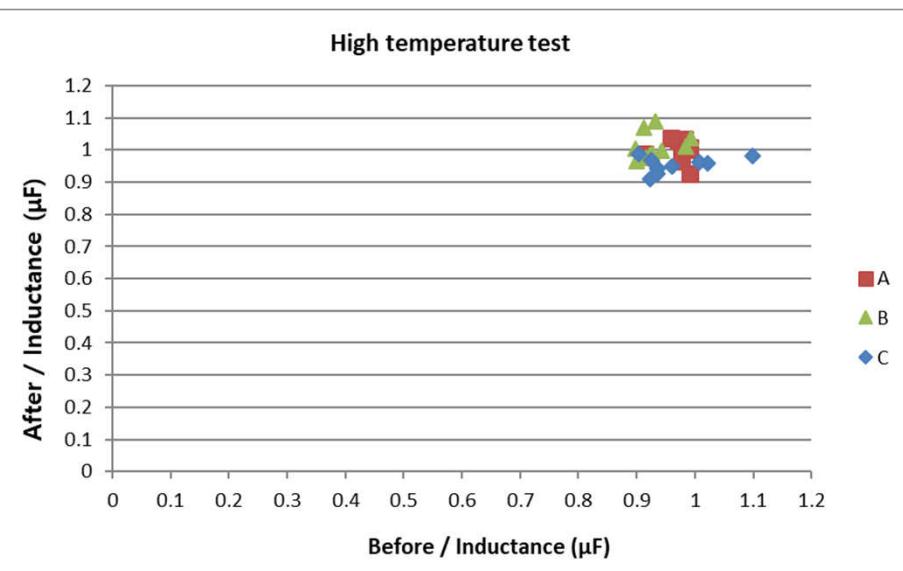


Environmental test conditions

- **Test:**
 - High temperature test: $(125 \pm 2)^\circ\text{C}$, 500 hr
 - Low temperature test: $(-40 \pm 2)^\circ\text{C}$, 500 hr
 - High temperature and high humidity operation test:
 $(85 \pm 2)^\circ\text{C}$, $(85 \pm 3)\%$ R.H., 1000 hr
 - Thermal shock test: $(125 \pm 2)^\circ\text{C}$, $(-40 \pm 2)^\circ\text{C}$, each 15 min., 500 cycles
 - Vibration test: (min 10 Hz, max 55 Hz), 1.52mm
(min 55 Hz, max 500 Hz), 98 m/s^2
each 2 hr/X,Y,Z

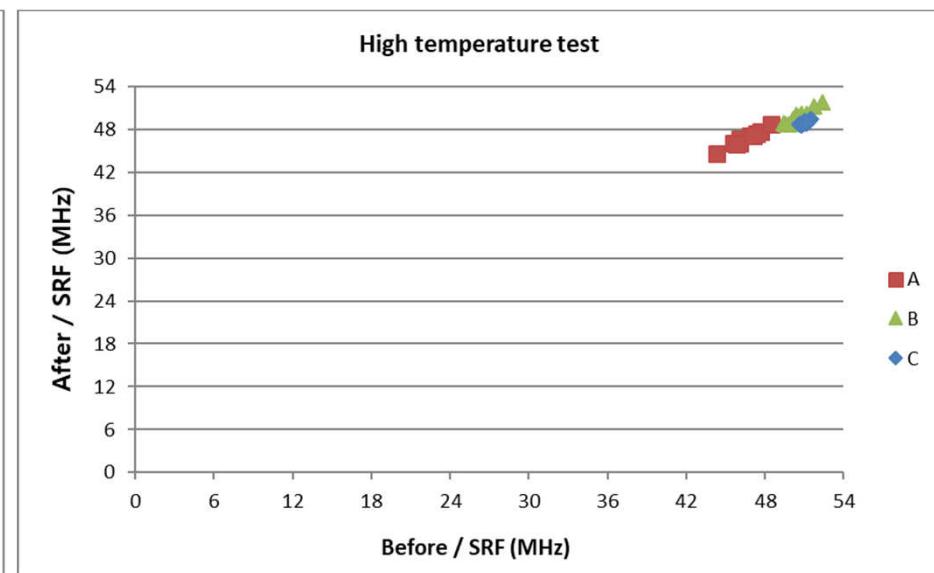
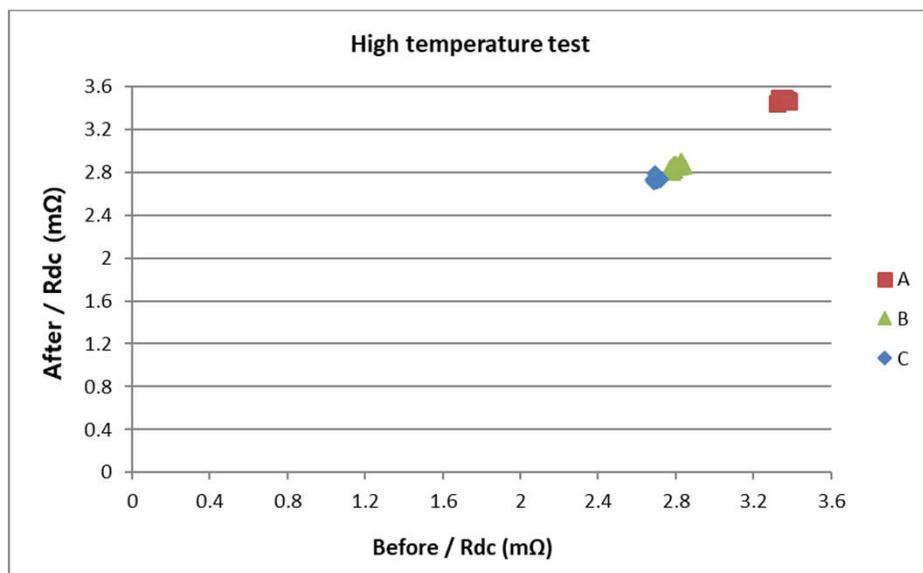
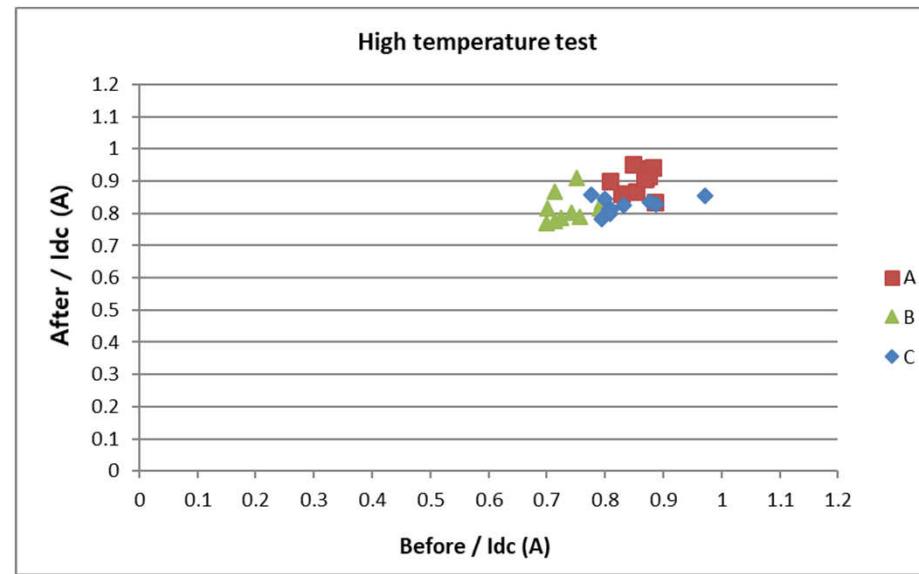
Summary

High temp. test



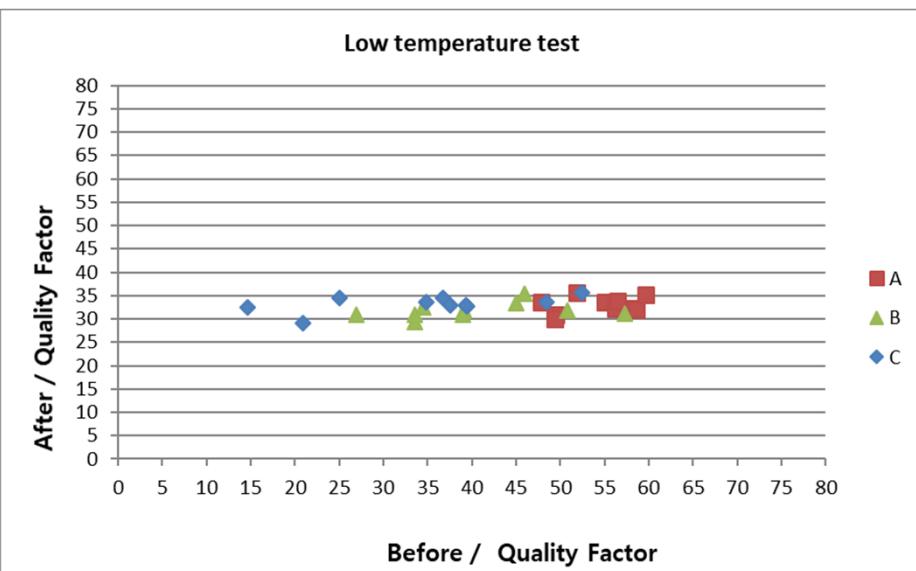
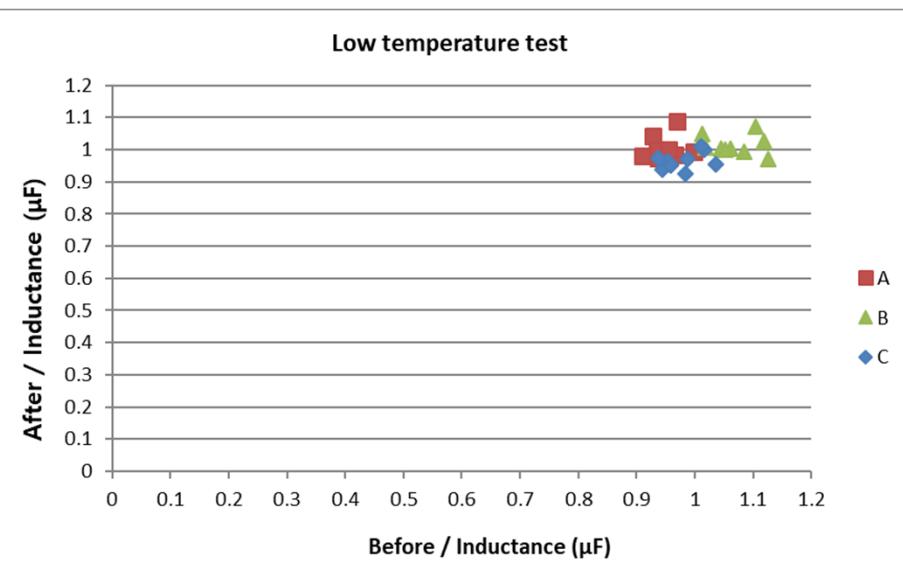
Summary

High temp. test



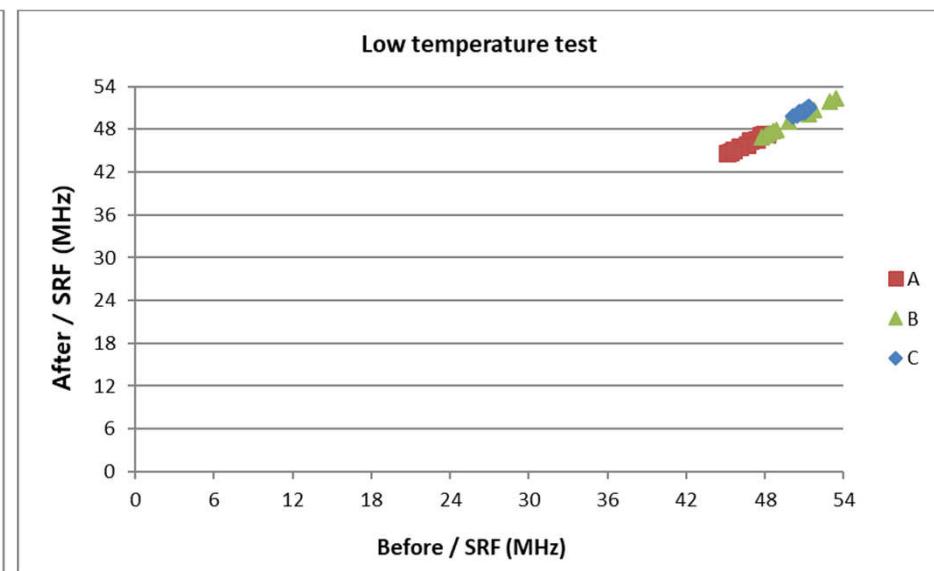
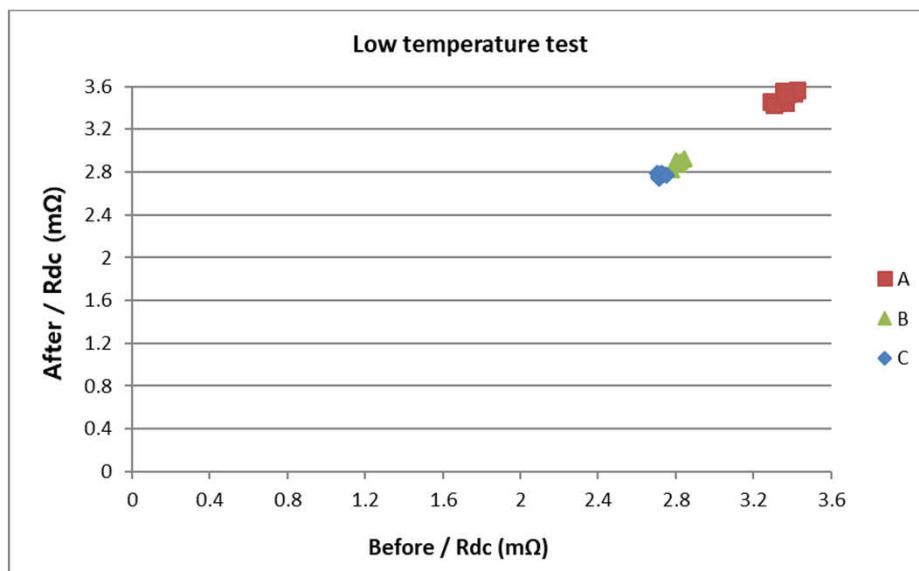
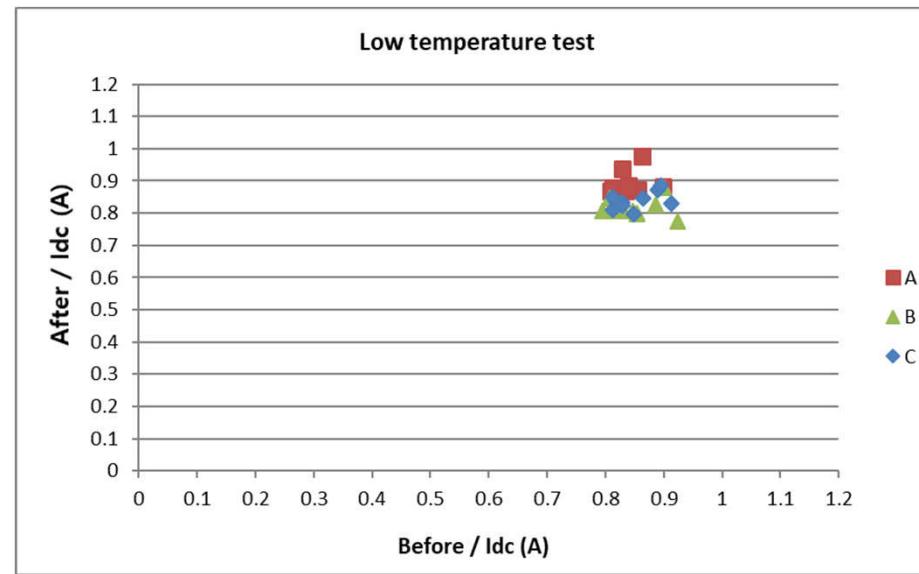
Summary

Low temp. test



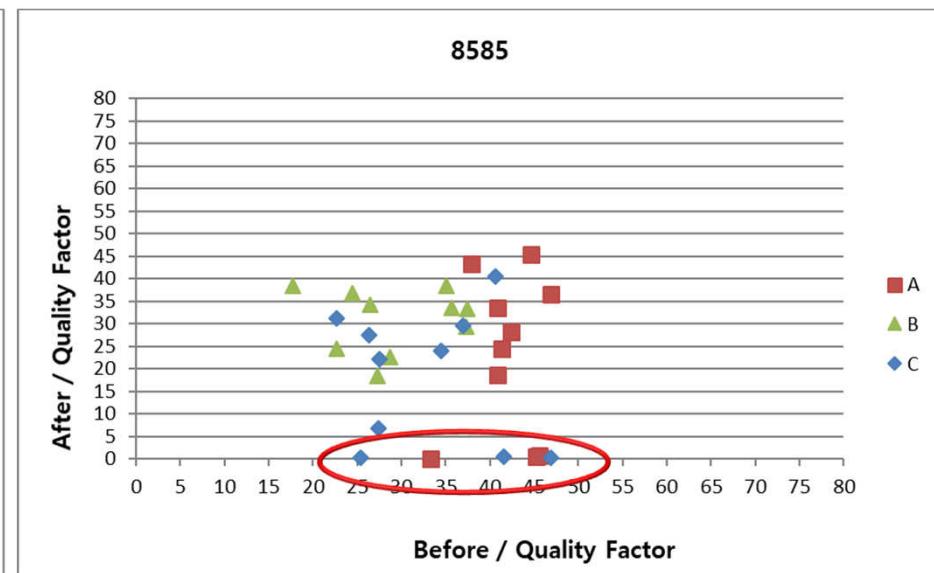
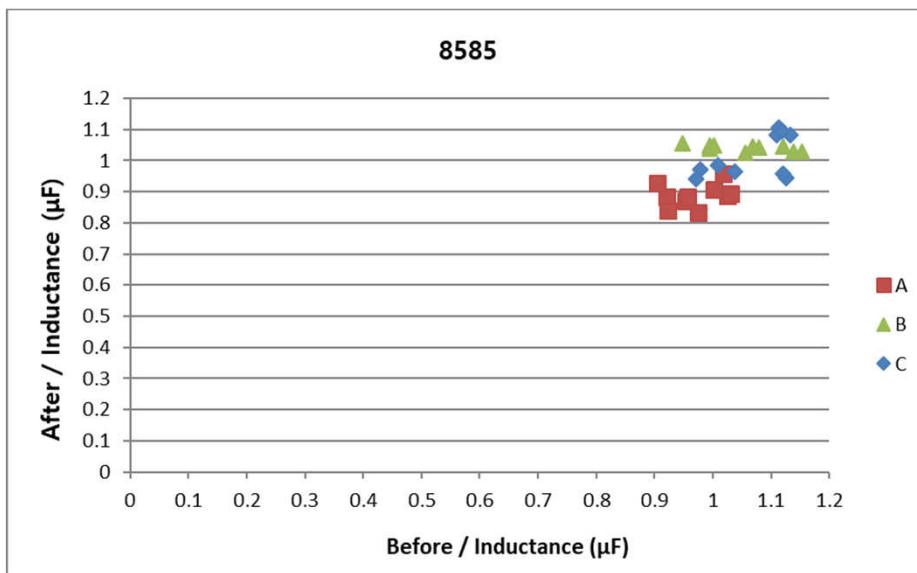
Summary

Low temp. test



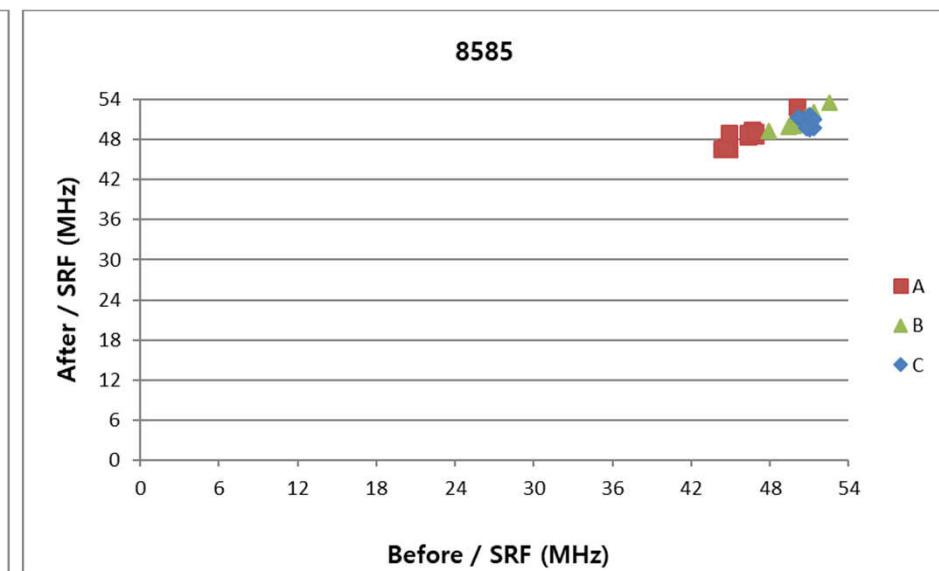
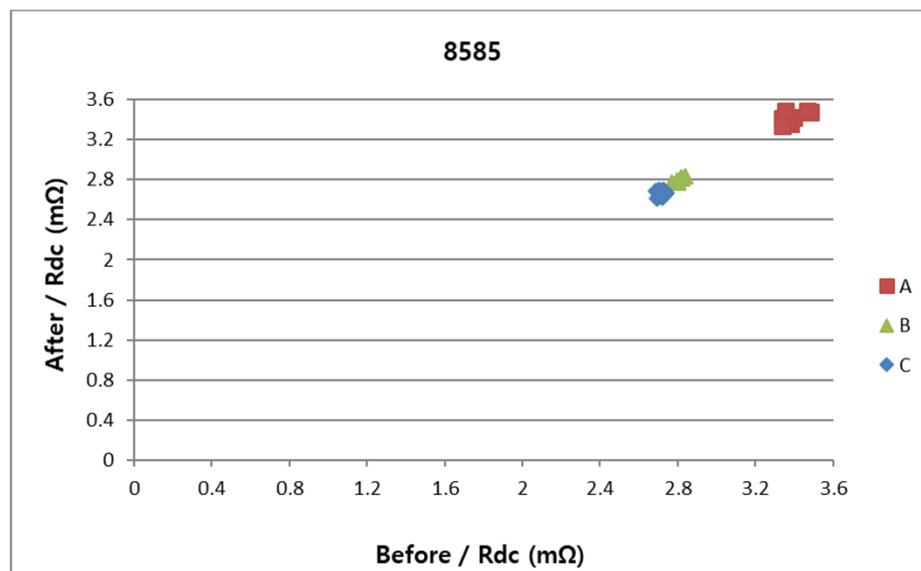
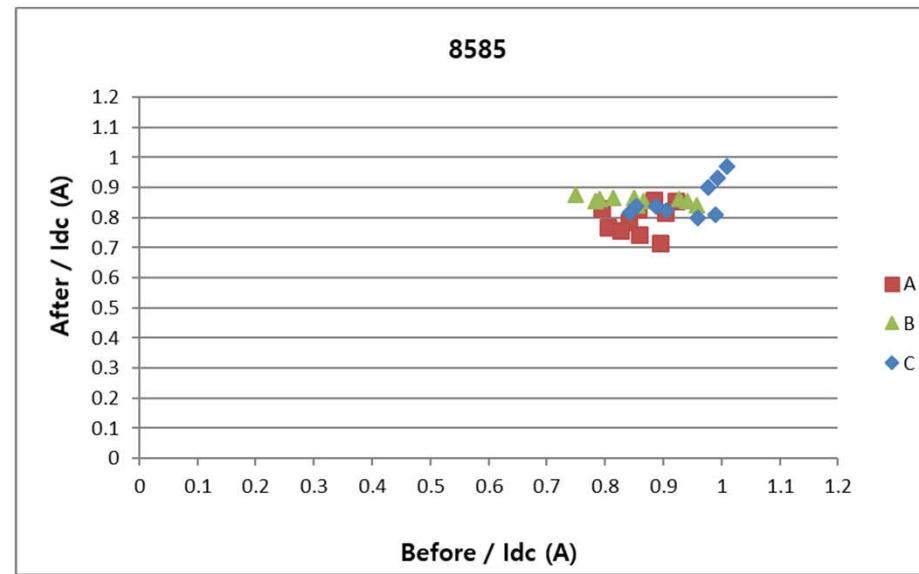
Summary

High temp. & high humidity



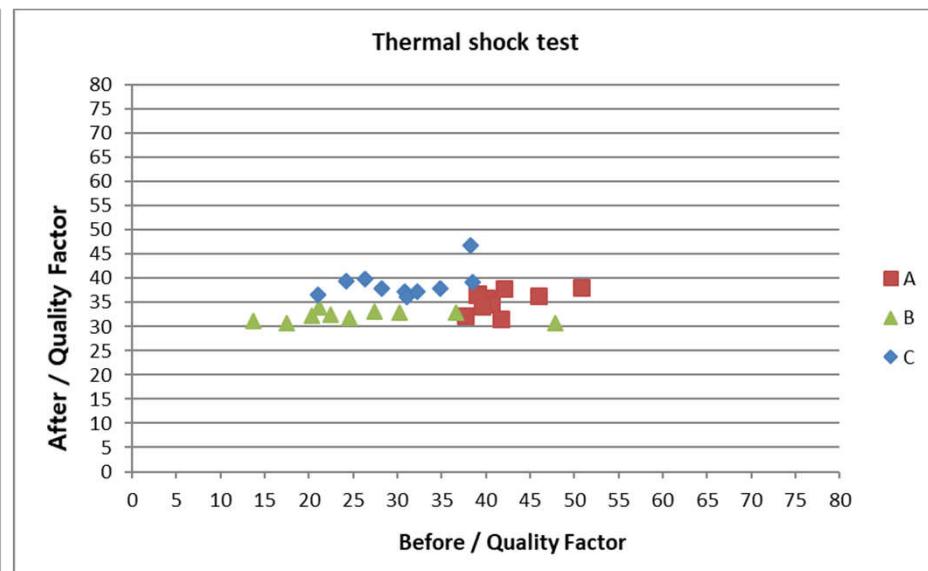
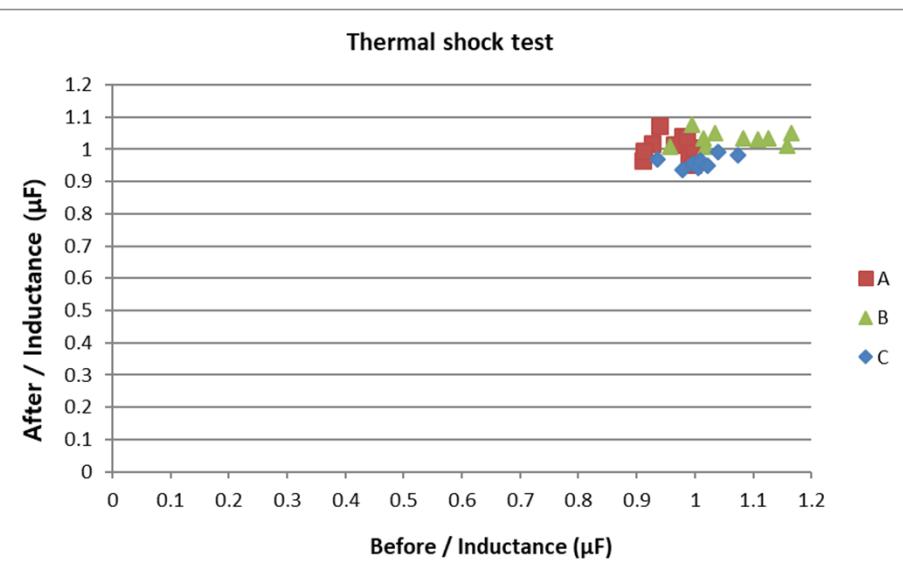
Summary

High temp. & high humidity



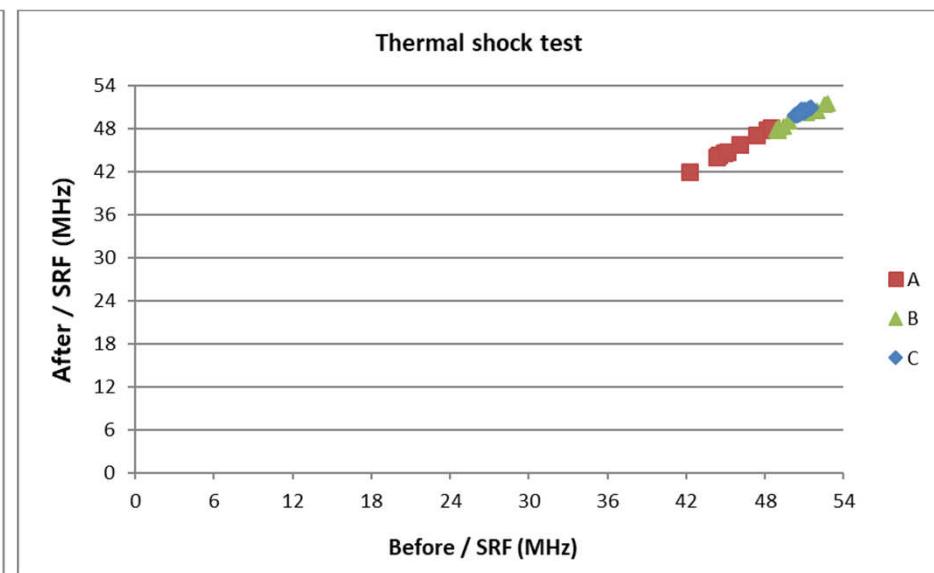
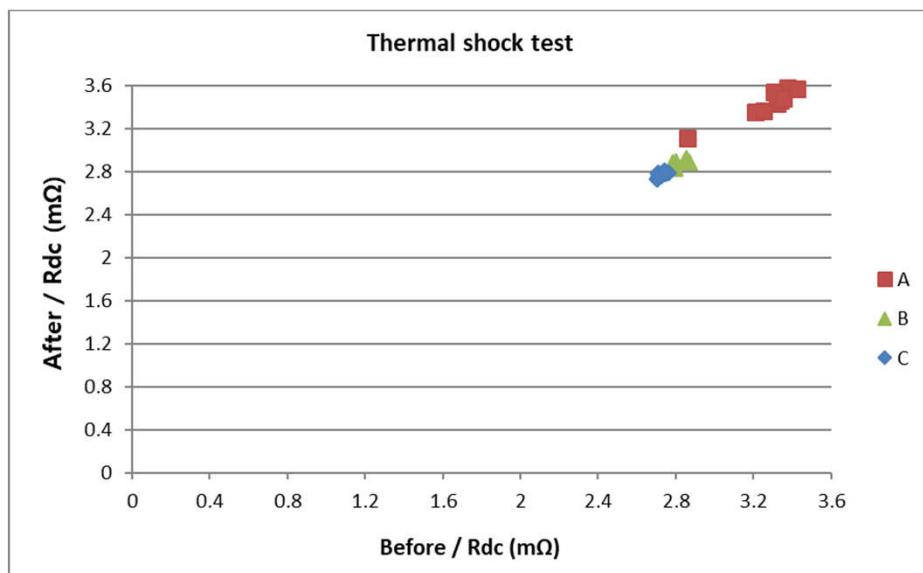
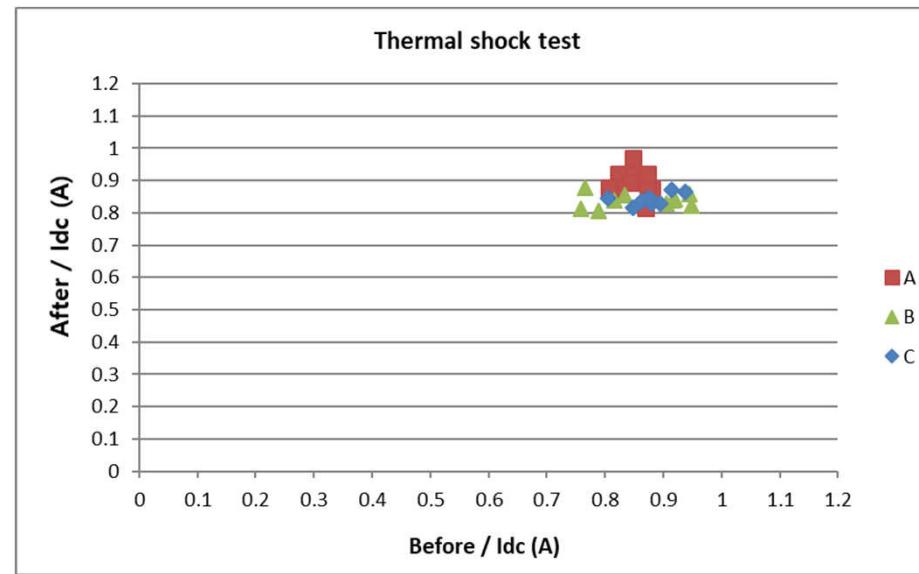
Summary

Thermal shock



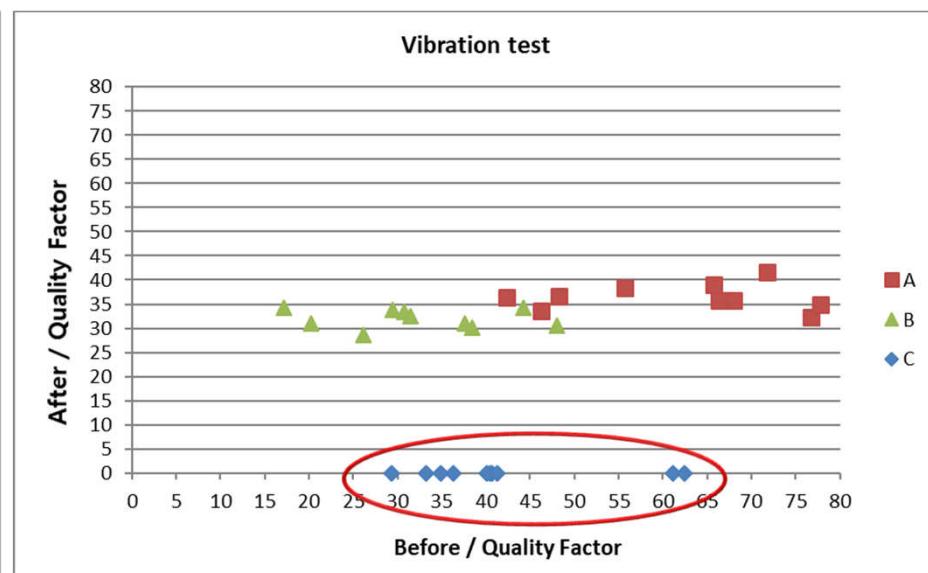
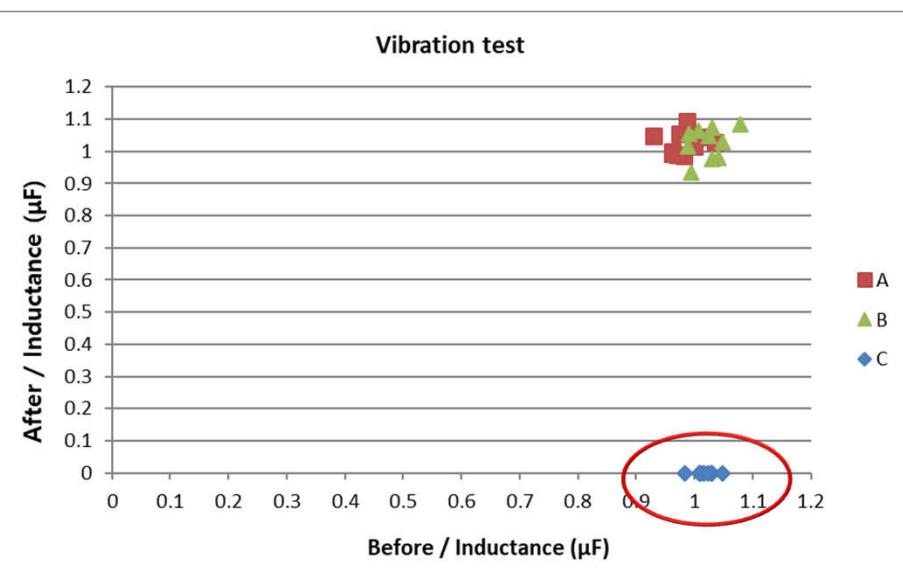
Summary

Thermal shock



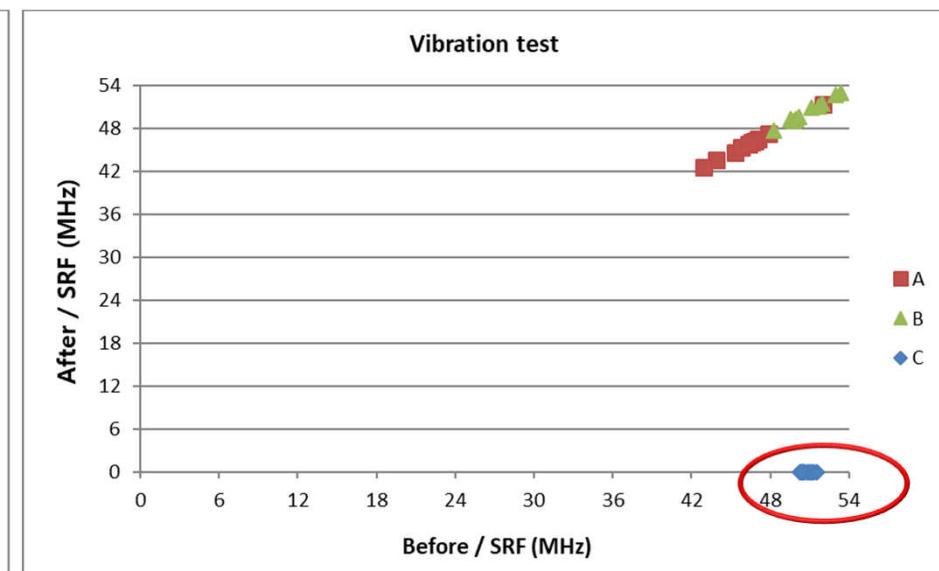
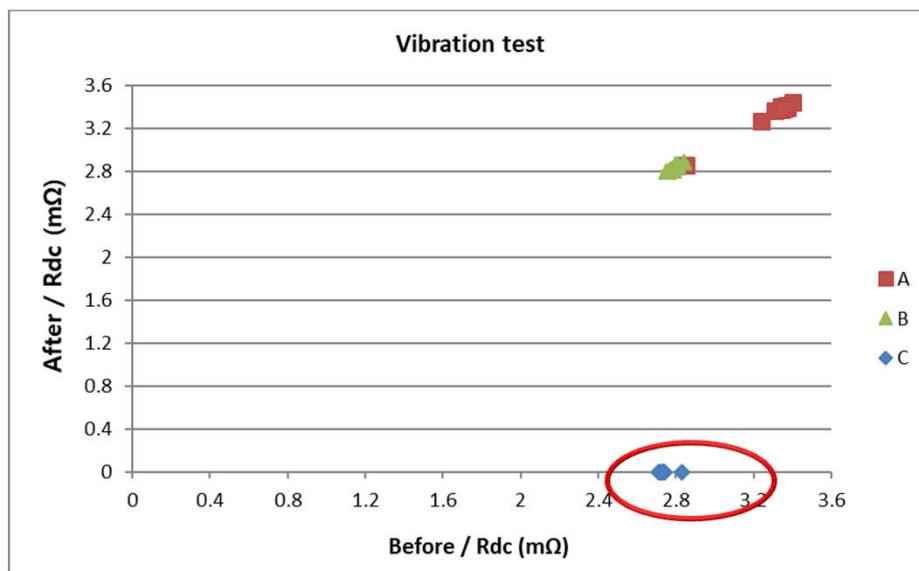
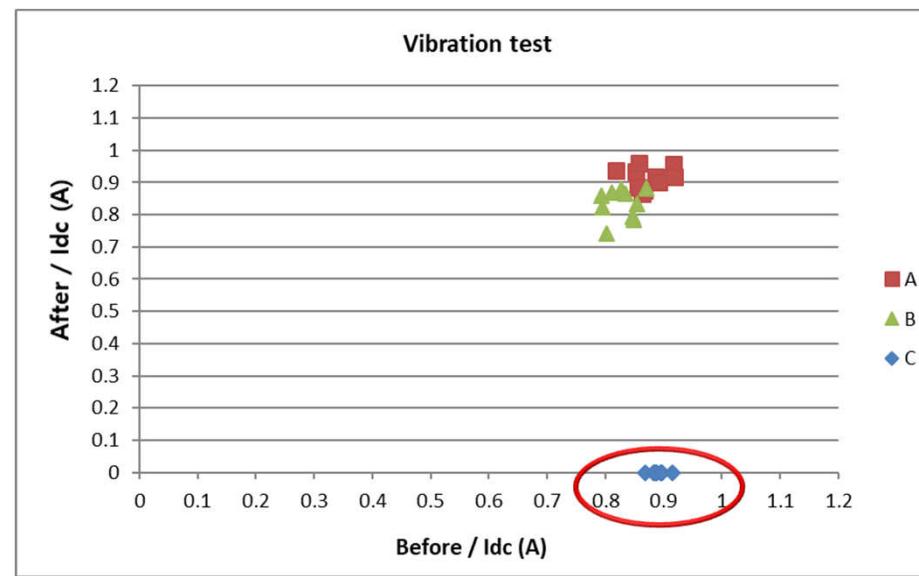
Summary

Vibration test



Summary

Vibration test



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High temp. test

High temperature test	Inductance (μF)			Quality Factor			Idc (A)			Rdc (m Ω)			SRF (MHz)		
	Before	After	Change rate (%)	Before	After	Change rate (%)	Before	After	Change rate (%)	Before	After	Change rate (%)	Before	After	Change rate (%)
#1	0.97	1.03	0.06	56.90	36.20	-0.57	0.87	0.94	0.07	3.36	3.48	0.03	47.38	47.38	0.00
#2	0.98	1.00	0.03	57.90	36.00	-0.61	0.87	0.91	0.04	3.32	3.45	0.04	46.09	46.09	0.00
#3	0.98	0.97	-0.01	58.10	31.60	-0.84	0.83	0.86	0.04	3.33	3.47	0.04	44.36	44.60	0.01
#4	0.98	1.03	0.05	59.70	29.10	-1.05	0.88	0.94	0.07	3.34	3.46	0.03	46.86	47.12	0.01
#5	0.96	1.04	0.07	54.50	39.60	-0.38	0.85	0.95	0.11	3.34	3.47	0.04	46.09	46.60	0.01
#6	0.99	1.01	0.02	60.80	36.60	-0.66	0.88	0.91	0.04	3.38	3.47	0.03	45.59	46.09	0.01
#7	0.95	9.64	0.90	86.20	31.90	-1.70	0.85	0.89	0.04	3.33	3.49	0.04	47.64	47.64	0.00
#8	0.99	1.00	0.01	62.10	35.40	-0.75	0.87	0.91	0.04	3.36	3.49	0.04	45.84	45.84	0.00
#9	0.99	0.92	-0.07	53.70	32.90	-0.63	0.89	0.84	-0.06	3.37	3.47	0.03	47.12	47.12	0.00
#10	0.91	0.99	0.07	47.70	30.50	-0.56	0.81	0.90	0.10	3.38	3.47	0.02	48.43	48.70	0.01
Average	0.97	1.86	0.11	59.76	33.98	-0.78	0.86	0.91	0.05	3.35	3.47	0.03	46.54	46.72	0.00

* Test condition: 1 MHz

B社**High temp. test**

High temperature test	Inductance (μF)			Quality Factor			Idc (A)			Rdc (m Ω)			SRF (MHz)		
	Before	After	Change rate (%)	Before	After	Change rate (%)	Before	After	Change rate (%)	Before	After	Change rate (%)	Before	After	Change rate (%)
#1	0.91	1.07	0.15	30.10	32.90	0.09	0.71	0.87	0.18	2.79	2.80	0.01	50.36	49.97	-0.01
#2	0.93	1.09	0.14	45.90	38.20	-0.20	0.75	0.91	0.17	2.82	2.85	0.01	50.75	50.17	-0.01
#3	0.99	1.04	0.04	32.50	32.30	-0.01	0.79	0.83	0.05	2.80	2.82	0.01	49.40	48.83	-0.01
#4	0.94	1.00	0.06	57.80	34.30	-0.69	0.74	0.80	0.07	2.80	2.88	0.03	49.59	48.64	-0.02
#5	0.98	1.01	0.03	15.70	31.80	0.51	0.79	0.82	0.03	2.85	2.86	0.00	52.35	51.74	-0.01
#6	0.90	0.96	0.07	31.80	32.70	0.03	0.70	0.77	0.09	2.83	2.90	0.03	51.74	51.15	-0.01
#7	0.93	0.99	0.06	25.30	31.80	0.20	0.72	0.78	0.08	2.77	2.82	0.02	50.17	49.40	-0.02
#8	0.92	0.97	0.06	49.70	31.80	-0.56	0.71	0.78	0.08	2.77	2.85	0.03	50.56	49.78	-0.02
#9	0.92	0.99	0.06	36.50	32.90	-0.11	0.76	0.79	0.04	2.79	2.87	0.03	49.78	48.64	-0.02
#10	0.90	1.01	0.11	44.80	33.20	-0.35	0.70	0.82	0.14	2.80	2.87	0.02	51.15	50.17	-0.02
Average	0.93	1.01	0.08	37.01	33.19	-0.11	0.74	0.82	0.09	2.80	2.85	0.02	50.58	49.85	-0.01

* Test condition: 100 kHz

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High temp. test

High temperature test	Inductance (μF)			Quality Factor			Idc (A)			Rdc (m Ω)			SRF (MHz)		
	Before	After	Change rate (%)	Before	After	Change rate (%)	Before	After	Change rate (%)	Before	After	Change rate (%)	Before	After	Change rate (%)
#1	1.02	0.96	-0.07	36.60	38.30	0.04	0.89	0.83	-0.07	2.71	2.73	0.01	50.80	48.57	-0.05
#2	0.92	0.91	-0.01	16.20	36.40	0.55	0.79	0.78	-0.01	2.70	2.74	0.01	50.80	48.74	-0.04
#3	0.96	0.95	-0.01	31.10	37.00	0.16	0.83	0.83	-0.01	2.72	2.73	0.00	50.98	49.07	-0.04
#4	0.90	0.99	0.09	66.60	39.50	-0.69	0.78	0.86	0.10	2.68	2.73	0.02	50.63	48.74	-0.04
#5	1.01	0.96	-0.05	30.60	36.50	0.16	0.88	0.83	-0.05	2.70	2.72	0.01	51.16	48.90	-0.05
#6	0.92	0.97	0.05	40.30	33.70	-0.20	0.80	0.84	0.05	2.69	2.71	0.01	51.51	49.42	-0.04
#7	0.94	0.94	0.01	32.80	35.40	0.07	0.81	0.81	0.01	2.69	2.74	0.02	50.80	48.74	-0.04
#8	0.94	0.94	0.01	20.30	38.20	0.47	0.81	0.81	0.00	2.72	2.74	0.01	50.98	48.90	-0.04
#9	0.93	0.93	-0.01	25.70	34.90	0.26	0.81	0.80	-0.01	2.70	2.72	0.01	51.34	49.07	-0.05
#10	1.10	0.98	-0.12	29.30	38.80	0.24	0.97	0.86	-0.13	2.69	2.79	0.03	51.16	48.90	-0.05
Average	0.96	0.95	-0.01	32.95	36.87	0.11	0.84	0.83	-0.01	2.70	2.73	0.01	51.02	48.90	-0.04

* Test condition: 100 kHz

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Low temp. test

Low temperature test	Inductance (μF)			Quality Factor			Idc (A)			Rdc (m Ω)			SRF (MHz)		
	Before	After	Change rate (%)	Before	After	Change rate (%)	Before	After	Change rate (%)	Before	After	Change rate (%)	Before	After	Change rate (%)
#1	0.93	1.04	0.11	47.90	33.60	-0.43	0.83	0.94	0.12	3.40	3.55	0.04	47.90	47.38	-0.01
#2	0.95	0.98	0.04	49.50	30.80	-0.61	0.83	0.87	0.04	3.41	3.54	0.04	47.64	47.12	-0.01
#3	1.00	0.99	-0.01	51.90	35.60	-0.46	0.90	0.88	-0.02	3.37	3.53	0.04	45.34	44.85	-0.01
#4	0.97	0.98	0.02	49.40	29.90	-0.65	0.86	0.87	0.02	3.36	3.45	0.03	47.38	46.60	-0.02
#5	0.94	0.97	0.04	58.40	32.30	-0.81	0.83	0.87	0.04	3.29	3.46	0.05	46.86	46.35	-0.01
#6	0.94	0.99	0.05	55.10	33.50	-0.64	0.84	0.89	0.05	3.30	3.43	0.04	46.60	45.84	-0.02
#7	0.94	1.00	0.07	56.20	32.30	-0.74	0.81	0.88	0.07	3.41	3.53	0.03	46.09	45.59	-0.01
#8	0.97	1.09	0.11	56.50	33.90	-0.67	0.86	0.98	0.12	3.43	3.57	0.04	45.09	44.60	-0.01
#9	0.91	0.98	0.07	58.60	32.00	-0.83	0.81	0.87	0.07	3.36	3.55	0.06	48.16	47.38	-0.02
#10	0.96	1.00	0.04	59.70	35.10	-0.70	0.84	0.88	0.05	3.37	3.51	0.04	45.59	45.09	-0.01
Average	0.95	1.00	0.05	54.32	32.90	-0.65	0.84	0.89	0.06	3.37	3.51	0.04	46.67	46.08	-0.01

* Test condition: 1 MHz

B社**Low temp. test**

Low temperature test	Inductance (μ F)			Quality Factor			Idc (A)			Rdc (m Ω)			SRF (MHz)		
	Before	After	Change rate (%)	Before	After	Change rate (%)	Before	After	Change rate (%)	Before	After	Change rate (%)	Before	After	Change rate (%)
#1	1.06	1.00	-0.06	34.50	32.50	-0.06	0.82	0.81	-0.02	2.80	2.87	0.03	47.71	46.80	-0.02
#2	1.02	1.01	-0.01	33.60	30.30	-0.11	0.83	0.81	-0.03	2.81	2.87	0.02	51.74	50.75	-0.02
#3	1.13	0.97	-0.16	39.10	31.90	-0.23	0.92	0.77	-0.19	2.78	2.82	0.02	49.78	49.02	-0.02
#4	1.04	1.00	-0.04	39.00	30.90	-0.26	0.85	0.81	-0.05	2.84	2.93	0.03	51.34	50.17	-0.02
#5	1.05	1.00	-0.05	50.80	31.70	-0.60	0.85	0.80	-0.07	2.81	2.87	0.02	48.08	47.16	-0.02
#6	1.12	1.03	-0.09	45.00	33.40	-0.35	0.89	0.83	-0.07	2.82	2.90	0.03	48.83	47.89	-0.02
#7	1.10	1.07	-0.03	45.90	35.40	-0.30	0.90	0.88	-0.03	2.84	2.92	0.03	52.96	51.94	-0.02
#8	1.08	0.99	-0.09	57.30	31.20	-0.84	0.85	0.80	-0.07	2.81	2.90	0.03	53.37	52.35	-0.02
#9	1.02	1.01	-0.01	27.00	31.00	0.13	0.79	0.81	0.02	2.79	2.88	0.03	48.27	47.52	-0.02
#10	1.01	1.05	0.03	33.50	30.90	-0.08	0.81	0.85	0.04	2.80	2.91	0.04	48.64	47.71	-0.02
Average	1.06	1.01	-0.05	40.57	31.92	-0.27	0.85	0.81	-0.05	2.81	2.89	0.03	50.07	49.13	-0.02

* Test condition: 100 kHz

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Low temp. test

Low temperature test	Inductance (μF)			Quality Factor			Idc (A)			Rdc (m Ω)			SRF (MHz)		
	Before	After	Change rate (%)	Before	After	Change rate (%)	Before	After	Change rate (%)	Before	After	Change rate (%)	Before	After	Change rate (%)
#1	0.94	0.94	-0.01	36.80	34.60	-0.06	0.81	0.81	0.00	2.71	2.78	0.03	50.11	49.76	-0.01
#2	0.96	0.95	0.00	25.00	34.40	0.27	0.83	0.83	0.00	2.73	2.77	0.02	51.16	50.80	-0.01
#3	0.99	0.97	-0.02	39.50	32.80	-0.20	0.86	0.85	-0.02	2.71	2.79	0.03	51.34	50.98	-0.01
#4	1.02	1.00	-0.02	39.40	32.90	-0.20	0.89	0.87	-0.02	2.72	2.74	0.01	50.98	50.45	-0.01
#5	1.01	1.01	0.00	48.40	33.60	-0.44	0.90	0.89	-0.01	2.71	2.78	0.03	51.34	51.16	0.00
#6	0.95	0.96	0.01	37.60	32.90	-0.14	0.82	0.84	0.02	2.71	2.75	0.01	50.63	50.28	-0.01
#7	0.94	0.97	0.04	52.50	35.60	-0.47	0.81	0.85	0.04	2.74	2.78	0.02	50.80	50.45	-0.01
#8	1.04	0.96	-0.08	34.80	33.60	-0.04	0.91	0.83	-0.10	2.73	2.79	0.02	50.98	50.63	-0.01
#9	0.96	0.95	-0.01	14.70	32.50	0.55	0.83	0.82	-0.01	2.76	2.77	0.01	50.45	49.93	-0.01
#10	0.98	0.93	-0.06	20.90	29.20	0.28	0.85	0.80	-0.07	2.75	2.77	0.01	50.63	50.45	0.00
Average	0.98	0.96	-0.02	34.96	33.21	-0.05	0.85	0.84	-0.02	2.72	2.77	0.02	50.84	50.49	-0.01

* Test condition: 100 kHz

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High temp. & high humidity test

High temp. high humidity	Inductance (μ F)				Quality Factor				Idc (A)				Rdc (m Ω)				SRF (MHz)			
	Before	Mid	After	Change rate (%)	Before	Mid	After	Change rate (%)	Before	Mid	After	Change rate (%)	Before	Mid	After	Change rate (%)	Before	Mid	After	Change rate (%)
#1	0.95	0.95	0.87	-0.10	40.90	66.20	33.40	-18.3	0.84	0.86	0.79	-0.07	3.34	3.35	3.44	0.03	46.35	47.61	49.82	0.07
#2	0.96	0.94	0.90	-0.07	33.30	68.20	0.14	-99.6	0.86	0.85	0.81	-0.06	3.38	3.42	3.36	-0.01	46.60	47.90	49.51	0.06
#3	0.92	0.91	0.88	-0.04	42.40	69.70	28.20	-33.4	0.80	0.81	0.77	-0.05	3.35	3.51	3.39	0.01	46.86	47.38	48.70	0.04
#4	0.90	0.92	0.93	0.02	40.90	65.20	18.70	-54.3	0.80	0.82	0.83	0.04	3.48	3.51	3.48	0.00	46.35	47.64	48.96	0.05
#5	0.92	0.94	0.84	-0.10	44.60	71.30	45.40	1.8	0.83	0.85	0.76	-0.09	3.36	3.57	3.37	0.00	50.05	51.16	52.88	0.05
#6	1.02	0.95	0.93	-0.10	45.60	69.30	0.72	-98.4	0.90	0.86	0.82	-0.11	3.40	3.50	3.42	0.01	44.36	45.34	46.60	0.05
#7	1.00	1.01	0.91	-0.11	46.90	69.10	36.50	-22.2	0.89	0.90	0.72	-0.25	3.37	3.55	3.38	0.00	44.85	45.59	46.60	0.04
#8	1.02	0.98	0.96	-0.06	37.90	69.20	43.30	12.1	0.88	0.88	0.86	-0.03	3.47	3.53	3.52	0.01	44.60	45.84	46.86	0.05
#9	1.03	0.96	0.94	-0.10	45.30	68.30	0.61	-98.6	0.92	0.87	0.90	-0.03	3.36	3.51	3.48	0.04	46.86	47.84	47.44	0.01
#10	0.97	0.94	0.83	-0.17	41.40	79.00	24.50	-40.8	0.86	0.85	0.74	-0.16	3.34	3.40	3.34	0.00	44.85	47.38	48.96	0.08
Average	0.97	0.95	0.90	-0.08	41.92	69.55	23.15	-44.8	0.86	0.85	0.80	-0.08	3.38	3.48	3.42	0.01	46.17	47.37	48.63	0.05

* Test condition: 1 MHz

* 500시간 시험 후: 모든 시료에 녹 발생

1000시간 시험 후: 모든 시료에 녹이 발생하였으나 500시간 후에 관찰했을 때와 비슷함

※QF值に異常が発生している

B社

High temp. & high humidity test

High temp. high humidity	Inductance (μ F)				Quality Factor				Idc (A)				Rdc (m Ω)				SRF (MHz)			
	Before	Mid	After	Change rate (%)	Before	Mid	After	Change rate (%)	Before	Mid	After	Change rate (%)	Before	Mid	After	Change rate (%)	Before	Mid	After	Change rate (%)
#1	0.99	0.96	1.04	0.04	17.70	28.90	38.30	53.8	0.78	0.78	0.85	0.08	2.79	2.82	2.79	0.00	49.78	49.59	50.68	0.02
#2	1.12	1.01	1.05	-0.07	26.50	28.10	34.20	29.1	0.93	0.82	0.86	-0.07	2.77	2.81	2.77	0.00	49.40	48.83	49.97	0.01
#3	0.99	1.00	1.05	0.05	35.70	25.60	33.40	-6.4	0.79	0.81	0.86	0.08	2.84	2.86	2.83	0.00	50.75	50.17	51.54	0.02
#4	1.06	1.01	1.02	-0.03	28.70	28.80	22.50	-21.6	0.85	0.83	0.84	-0.02	2.79	2.83	2.77	-0.01	50.17	49.78	51.15	0.02
#5	1.14	1.04	1.03	-0.11	35.10	32.30	38.40	9.4	0.94	0.86	0.85	-0.10	2.82	2.86	2.81	0.00	52.55	52.14	53.58	0.02
#6	1.00	1.03	1.05	0.04	24.50	30.10	36.80	50.2	0.81	0.85	0.87	0.06	2.80	2.82	2.78	-0.01	49.78	49.59	50.75	0.02
#7	1.08	1.03	1.04	-0.03	27.30	29.00	18.30	33	0.87	0.85	0.86	-0.01	2.80	2.81	2.77	-0.01	49.59	49.40	50.36	0.02
#8	1.07	1.02	1.04	-0.02	37.40	29.00	33.30	-11	0.85	0.84	0.87	0.02	2.80	2.81	2.78	-0.01	49.97	49.78	50.95	0.02
#9	0.95	0.95	1.06	0.10	37.30	29.50	29.30	-21.5	0.75	0.77	0.88	0.15	2.82	2.86	2.82	0.00	51.34	50.95	52.14	0.02
#10	1.15	1.09	1.03	-0.12	22.70	33.20	24.50	7.9	0.96	0.91	0.84	-0.14	2.80	2.84	2.78	-0.01	47.89	47.89	49.21	0.03
Average	1.06	1.02	1.04	-0.01	29.29	29.45	30.90	5.5	0.85	0.83	0.86	0.00	2.80	2.83	2.79	-0.01	50.12	49.81	51.03	0.02

* Test condition: 100 kHz

* 500시간 시험 후: 외관 변화 없음

1000시간 시험 후: #1, #2, #5 시료의 모서리 부분 위주로 녹 발생

C社

High temp. & high humidity test

High temp. high humidity	Inductance (μ F)				Quality Factor				Idc (A)				Rdc (m Ω)				SRF (MHz)			
	Before	Mid	After	Change rate (%)	Before	Mid	After	Change rate (%)	Before	Mid	After	Change rate (%)	Before	Mid	After	Change rate (%)	Before	Mid	After	Change rate (%)
#1	1.04	0.99	0.96	-0.08	34.50	40.70	23.90	-30.7	0.91	0.86	0.82	-0.10	2.72	2.72	2.64	-0.03	50.45	48.40	50.98	0.01
#2	0.98	0.98	0.97	-0.01	26.40	35.10	27.40	3.8	0.85	0.85	0.84	-0.02	2.69	2.73	2.61	-0.03	50.98	48.90	49.59	-0.03
#3	1.01	0.97	0.98	-0.03	46.90	30.40	0.26	-99.5	0.89	0.84	0.83	-0.06	2.72	2.79	2.63	-0.04	51.34	49.93	49.76	-0.03
#4	0.97	0.97	0.94	-0.03	27.50	31.20	22.10	-19.6	0.84	0.85	0.82	-0.03	2.72	2.81	2.68	-0.01	50.80	49.79	49.65	-0.02
#5	1.13	1.00	0.94	-0.19	27.40	29.90	6.85	-75	0.96	0.88	0.80	-0.20	2.70	2.80	2.64	-0.02	50.98	48.40	50.45	-0.01
#6	1.11	1.06	1.08	-0.03	22.70	25.10	29.80	31.2	0.98	0.94	0.91	-0.08	2.73	2.74	2.69	-0.01	50.80	47.57	50.01	-0.02
#7	1.12	0.95	1.02	-0.10	25.40	33.00	0.15	-99.5	0.99	0.83	0.82	-0.21	2.74	2.74	2.67	-0.03	50.98	48.57	51.69	0.01
#8	1.13	1.13	1.13	0.00	37.00	36.90	31.40	-15.1	1.01	0.98	0.99	-0.02	2.69	2.78	2.63	-0.02	51.34	47.24	50.49	-0.02
#9	1.11	1.09	1.08	-0.03	40.60	32.40	40.00	-1.5	1.00	0.96	9.55	0.90	2.71	2.79	2.71	0.00	50.80	49.04	50.31	-0.01
#10	1.12	1.04	1.06	-0.06	41.60	21.90	0.45	-98.9	0.99	0.91	0.95	-0.05	2.71	2.80	2.64	-0.03	50.11	48.40	51.34	0.02
Average	1.07	1.02	1.02	-0.06	33.00	31.66	18.23	-44.8	0.94	0.89	1.73	0.01	2.71	2.77	2.65	-0.02	50.86	48.62	50.43	-0.01

* Test condition: 100 kHz

* 500시간 시험 후: #4, #6, #7, #9 시료의 pin 부분에 녹 발생, #10 시료 모서리 부분 깨짐

1000시간 시험 후: #3, #5 시료를 제외한 모든 시료에 녹 발생, #7 시료 모서리 부분 깨짐

※QF值に異常が発生している

A社

Thermal shock test

Thermal shock test	Inductance (μF)			Quality Factor			Idc (A)			Rdc (m Ω)			SRF (MHz)		
	Before	After	Change rate (%)	Before	After	Change rate (%)	Before	After	Change rate (%)	Before	After	Change rate (%)	Before	After	Change rate (%)
#1	0.93	1.02	0.09	45.90	36.30	-0.26	0.82	0.92	0.11	3.32	3.43	0.03	48.16	47.90	-0.01
#2	0.98	1.04	0.06	50.80	38.10	-0.33	0.85	0.92	0.07	3.38	3.58	0.06	44.85	44.60	-0.01
#3	0.99	0.98	-0.01	40.00	36.00	-0.11	0.88	0.87	-0.01	3.34	3.46	0.04	47.38	47.12	-0.01
#4	0.97	1.02	0.05	39.10	36.70	-0.07	0.84	0.89	0.06	3.21	3.36	0.04	44.50	44.36	0.00
#5	0.91	0.97	0.06	42.10	37.90	-0.11	0.82	0.88	0.06	3.34	3.49	0.04	48.43	48.16	-0.01
#6	1.00	1.01	0.01	40.70	34.70	-0.17	0.87	0.89	0.01	3.31	3.54	0.07	44.36	44.11	-0.01
#7	0.91	1.00	0.08	37.70	32.30	-0.17	0.81	0.88	0.08	3.36	3.48	0.04	46.09	45.84	-0.01
#8	1.00	0.95	-0.05	41.70	31.60	-0.32	0.87	0.82	-0.07	2.86	3.11	0.08	42.22	41.98	-0.01
#9	0.99	1.04	0.05	39.00	36.60	-0.07	0.87	0.92	0.05	3.43	3.57	0.04	45.09	44.85	-0.01
#10	0.94	1.07	0.12	39.60	34.20	-0.16	0.85	0.97	0.12	3.25	3.37	0.03	46.09	45.84	-0.01
Average	0.96	1.01	0.05	41.66	35.44	-0.18	0.85	0.90	0.05	3.28	3.44	0.05	45.72	45.48	-0.01

* Test condition: 1 MHz

B社

Thermal shock test

Thermal shock test	Inductance (μF)			Quality Factor			Idc (A)			Rdc (m Ω)			SRF (MHz)		
	Before	After	Change rate (%)	Before	After	Change rate (%)	Before	After	Change rate (%)	Before	After	Change rate (%)	Before	After	Change rate (%)
#1	1.00	1.08	0.08	24.60	31.90	0.23	0.77	0.88	0.13	2.80	2.90	0.03	49.02	47.71	-0.03
#2	1.01	1.03	0.02	21.20	33.90	0.37	0.82	0.84	0.03	2.80	2.84	0.02	48.83	47.89	-0.02
#3	1.08	1.03	-0.05	30.20	32.80	0.08	0.91	0.83	-0.09	2.79	2.84	0.02	49.02	48.08	-0.02
#4	1.02	1.01	-0.01	27.40	33.20	0.17	0.79	0.81	0.02	2.80	2.83	0.01	49.78	49.02	-0.02
#5	1.11	1.03	-0.08	20.30	32.20	0.37	0.92	0.84	-0.09	2.79	2.88	0.03	51.94	50.56	-0.03
#6	1.16	1.01	-0.14	36.60	32.80	-0.12	0.95	0.82	-0.15	2.85	2.91	0.02	52.75	51.54	-0.02
#7	1.13	1.04	-0.09	22.40	32.40	0.31	0.92	0.84	-0.09	2.85	2.93	0.03	50.95	50.17	-0.02
#8	1.03	1.05	0.02	17.50	30.80	0.43	0.83	0.85	0.02	2.78	2.84	0.02	49.40	48.27	-0.02
#9	0.96	1.01	0.05	13.70	31.10	0.56	0.76	0.81	0.07	2.87	2.89	0.01	51.15	50.17	-0.02
#10	1.17	1.05	-0.11	47.80	30.80	-0.55	0.94	0.86	-0.10	2.86	2.90	0.01	52.55	51.34	-0.02
Average	1.07	1.03	-0.03	26.17	32.19	0.19	0.86	0.84	-0.03	2.82	2.88	0.02	50.54	49.47	-0.02

* Test condition: 100 kHz

C社

Thermal shock test

Thermal shock test	Inductance (μF)			Quality Factor			Idc (A)			Rdc (m Ω)			SRF (MHz)		
	Before	After	Change rate (%)	Before	After	Change rate (%)	Before	After	Change rate (%)	Before	After	Change rate (%)	Before	After	Change rate (%)
#1	1.01	0.97	-0.04	32.30	37.30	15.5	0.88	0.85	-0.03	2.71	2.75	0.01	50.98	50.28	-0.01
#2	1.04	0.99	-0.05	26.30	39.80	51.3	0.91	0.87	-0.05	2.77	2.79	0.01	51.51	50.98	-0.01
#3	1.00	0.95	-0.05	30.90	37.30	20.7	0.88	0.84	-0.05	2.71	2.79	0.03	51.34	50.80	-0.01
#4	1.00	0.96	-0.04	34.90	37.90	8.6	0.86	0.83	-0.03	2.75	2.78	0.01	50.45	50.11	-0.01
#5	0.94	0.97	0.04	28.20	38.00	34.8	0.80	0.85	0.05	2.70	2.73	0.01	50.28	49.93	-0.01
#6	1.07	0.98	-0.09	24.20	39.40	62.8	0.94	0.86	-0.08	2.70	2.73	0.01	50.80	50.28	-0.01
#7	0.98	0.94	-0.04	21.00	36.50	73.8	0.85	0.82	-0.04	2.72	2.76	0.01	50.98	50.63	-0.01
#8	1.01	0.94	-0.07	38.50	39.10	1.6	0.88	0.83	-0.06	2.72	2.76	0.01	50.80	50.63	0.00
#9	1.01	0.96	-0.05	38.30	46.80	22.2	0.88	0.84	-0.04	2.71	2.78	0.03	50.45	49.93	-0.01
#10	1.02	0.95	-0.08	31.10	36.10	14.2	0.90	0.83	-0.08	2.74	2.81	0.02	50.63	50.11	-0.01
Average	1.01	0.96	-0.05	30.57	38.82	26.9	0.88	0.84	-0.04	2.72	2.77	0.02	50.82	50.37	-0.01

* Test condition: 100 kHz

A社

Vibration test

Vibration test	Inductance (μF)			Quality Factor			Idc (A)			Rdc ($\text{m}\Omega$)			SRF (MHz)		
	Before	After	Change rate (%)	Before	After	Change rate (%)	Before	After	Change rate (%)	Before	After	Change rate (%)	Before	After	Change rate (%)
#1	0.96	1.00	4.2	42.30	36.50	-13.1	0.89	0.92	0.03	3.37	3.40	0.01	52.01	51.45	-0.01
#2	0.98	0.99	1	46.20	33.60	-27.2	0.86	0.86	0.00	3.40	3.45	0.01	43.87	43.63	-0.01
#3	1.01	1.04	3	68.00	35.80	-47.4	0.92	0.96	0.04	3.34	3.37	0.01	47.90	47.38	-0.01
#4	0.93	1.05	12.9	71.80	41.70	-41.9	0.82	0.94	0.12	3.34	3.41	0.02	47.12	46.60	-0.01
#5	0.98	1.06	8	65.70	39.10	-40.5	0.85	0.94	0.09	3.37	3.40	0.01	46.86	46.35	-0.01
#6	0.97	0.99	2.1	48.30	36.70	-24	0.87	0.88	0.01	3.31	3.37	0.02	45.34	44.60	-0.02
#7	0.96	0.99	3.1	76.70	32.20	-58	0.86	0.89	0.03	3.24	3.27	0.01	46.60	46.09	-0.01
#8	1.04	1.03	-1	77.80	34.90	-55.1	0.92	0.92	0.00	3.37	3.41	0.01	45.84	45.34	-0.01
#9	0.99	1.09	10.1	55.70	38.30	-45	0.86	0.96	0.11	2.85	2.86	0.00	42.92	42.68	-0.01
#10	1.00	1.01	10	66.40	35.70	-46.2	0.89	0.90	0.01	3.36	3.39	0.01	46.35	45.84	-0.01
Average	0.98	1.02	4.1	61.89	36.45	-41.1	0.87	0.92	0.05	3.30	3.33	0.01	46.48	46.00	-0.01

* Test condition: 1 MHz

B社

Vibration test

Vibration test	Inductance (μF)			Quality Factor			Idc (A)			Rdc ($\text{m}\Omega$)			SRF (MHz)		
	Before	After	Change rate (%)	Before	After	Change rate (%)	Before	After	Change rate (%)	Before	After	Change rate (%)	Before	After	Change rate (%)
#1	0.99	0.93	-6.1	17.20	34.30	51	0.80	0.74	-0.08	2.84	2.89	0.02	51.94	51.54	-0.01
#2	1.04	0.98	-5.8	26.10	28.70	10	0.85	0.78	-0.08	2.81	2.84	0.01	51.15	50.95	0.00
#3	0.99	1.02	3	30.80	33.30	8.1	0.80	0.82	0.03	2.76	2.80	0.02	49.59	49.40	0.00
#4	1.05	1.03	-1.9	20.20	30.90	53	0.85	0.83	-0.03	2.78	2.82	0.02	49.78	49.02	-0.02
#5	1.03	0.98	-4.9	29.50	33.90	14.9	0.85	0.79	-0.07	2.81	2.87	0.02	52.96	52.75	0.00
#6	1.03	1.05	1.9	38.40	30.10	-21.6	0.84	0.86	0.03	2.79	2.82	0.01	53.37	52.96	-0.01
#7	1.03	1.07	3.9	37.60	30.90	-17.8	0.83	0.88	0.06	2.75	2.80	0.02	49.97	49.40	-0.01
#8	1.01	1.06	5	31.50	32.50	3.2	0.81	0.87	0.07	2.77	2.82	0.02	50.17	49.59	-0.01
#9	0.99	1.06	6	48.00	30.60	-36.3	0.79	0.86	0.08	2.80	2.87	0.03	51.74	51.15	-0.01
#10	1.08	1.08	0.00	44.20	34.30	-22.4	0.87	0.88	0.01	2.81	2.85	0.02	48.27	47.71	-0.01
Average	1.02	1.03	1	32.35	31.95	-1.2	0.83	0.83	0.00	2.79	2.84	0.02	50.89	50.45	-0.01

* Test condition: 100 kHz

Vibration test	Inductance (μF)			Quality Factor			Idc (A)			Rdc ($\text{m}\Omega$)			SRF (MHz)		
	Before	After	Change rate (%)	Before	After	Change rate (%)	Before	After	Change rate (%)	Before	After	Change rate (%)	Before	After	Change rate (%)
#1	1.03	0.84	-18.5	61.20	26.90	-56	0.90	0.77	-0.16	2.71	2.63	-0.03	50.63	62.20	0.19
#2	0.98	0.93	-5.1	62.50	27.00	-56.8	0.87	0.83	-0.04	2.71	2.62	-0.04	50.98	55.00	0.07
#3	1.03	0.68	-33.4	36.30	13.20	-63.6	0.90	0.63	-0.43	2.74	2.64	-0.04	51.34	67.45	0.24
#4	1.02	0.88	-13.7	29.30	17.90	-38.9	0.89	0.77	-0.15	2.74	2.63	-0.04	50.28	54.25	0.07
#5	1.02	0.70	-31.4	34.90	14.20	-59.3	0.89	0.63	-0.42	2.72	2.63	-0.04	50.80	64.15	0.21
#6	1.01	0.91	-9.9	33.20	16.60	-50	0.89	0.77	-0.15	2.74	2.62	-0.05	51.16	51.40	0.00
#7	1.05	0.71	-32.4	40.70	17.30	-57.5	0.92	0.64	-0.43	2.74	2.63	-0.04	50.45	62.95	0.20
#8	1.01	0.42	-58.4	40.50	6.20	-84.7	0.88	0.40	-1.22	2.83	2.63	-0.08	50.63	109.10	0.54
#9	1.01	0.85	-15.8	40.10	17.10	-57.4	0.88	0.75	-0.17	2.73	2.63	-0.04	50.45	57.55	0.12
#10	1.02	0.54	-60.8	41.30	13.50	-67.3	0.90	0.50	-0.80	2.73	2.64	-0.03	51.51	77.45	0.33
Average	1.02	0.75	-26.5	42.00	16.99	-59.6	0.89	0.67	-0.40	2.74	2.63	-0.04	50.82	66.15	0.20

* Test condition: 100 kHz

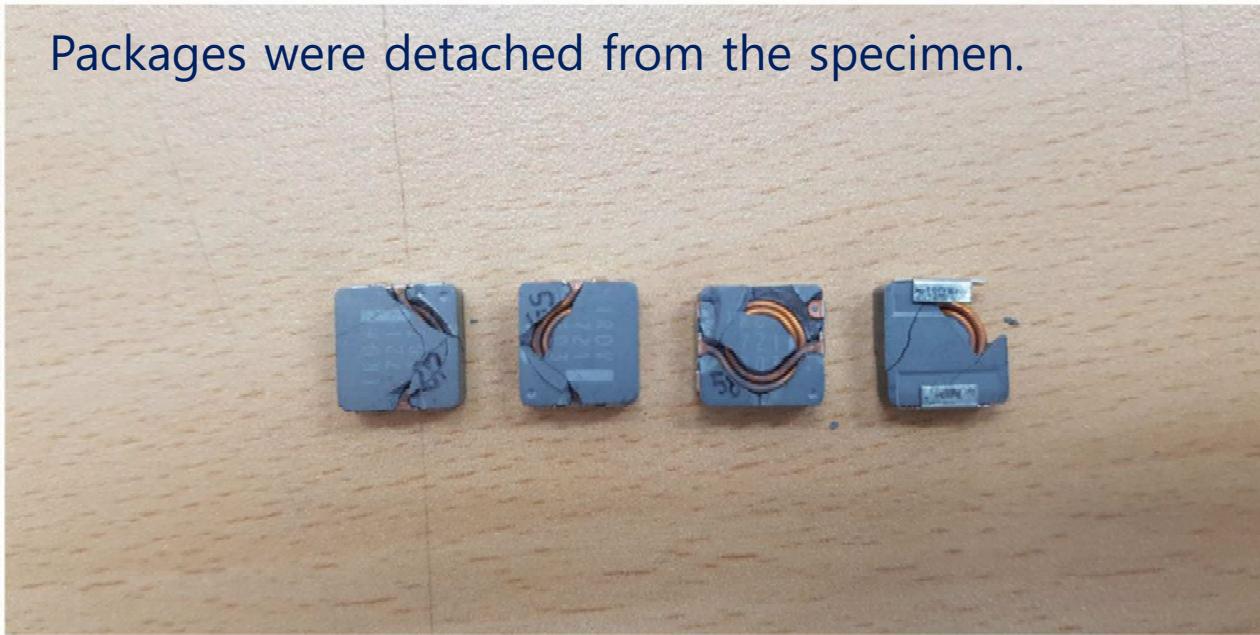
- In the case of sample C, all the specimen got fractured during vibration test (Z-axis).

Please refer picture on the next page.

※試験後、サンプルは全て破壊/クラックが発生している。そして、インダクタンス値は規格オーバーしている。

<2 types of failures sample C after vibration test>

Packages were detached from the specimen.

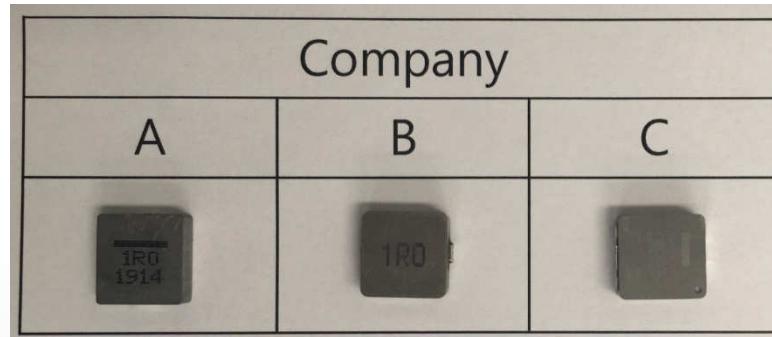


Crack formation on the packages



KETI試験結果のまとめ考察

1. 試験サンプル製品仕様詳細



Sample	Inductance		R_{dc} (max) (mΩ)	Test Frequency(Hz)	Operation temp. (°C)
	L (uH)	Tol. (%)			
A	1.0	±20	3.2	1 M	-40 ~ +125
B	1.0	±20	3.1	100 K	-55 ~ +125
C	1.0	±20	2.86	100 K	unknown ~ +155

サンプル	メーカー	部品型番	仕様	外形寸法
A	Coilmaster	CMI-MMPP10040LL-1 ROM	1 uH±20%、Is=14.2A(ΔT=40deg)、DCR=3.2mΩ、Top=-40~125°C	10.85x10mm
B	Chilisin	BMRF001010401ROMD1	1 uH±20%、Is=26A(ΔT=40deg)、DCR=3.1 mΩ、Top=-55~125°C	11.6x10.1 mm
C	Panasonic	ETQ-P4M1 R0KVC	1 uH±20%、Is=23.9A(ΔT=40deg)、DCR=2.86mΩ、Top=-55~125°C	10.7x10mm

KETI試験結果のまとめ考察

2. 試験結果比較

試験項目	A:Coilmaster	B:Chilisin	C:パナソニック
X線解析	異常なし	異常なし	異常なし
SEM観察	異常なし	異常なし	異常なし
高温保存試験	問題無し(規格内)	問題無し(規格内)	問題無し(規格内)
低温保存試験	問題無し(規格内)	問題無し(規格内)	問題無し(規格内)
高温高湿保存試験	問題有り(QF値異常発生)	問題無し(規格内)	問題有り(QF値異常発生)
サーマルショック試験	問題無し(規格内)	問題無し(規格内)	問題無し(規格内)
振動試験	問題無し(規格内)	問題無し(規格内)	問題有り(インダクタンス規格値オーバー)

※補足

- ・A/C社製品は高温高湿保存試験で**QF値が異常**となるサンプルが数個発生している。
明確なスペック値の記載は無いが、インダクタ製品としては性能/機能問題である。
- ・C社製品は振動試験にて**クラックが発生**しており、インダクタンス**規格オーバー/QF特性**に異常が発生している。**構造的な欠陥**が有ると言える。

KETI試験結果のまとめ考察



3. 試験結果考察

①高温高湿保存試験について

2社 (Coilmaster/パナソニック) にて**QF値の異常**が数点発生している。**メタルコンポジットコア部材**が高温高湿の影響でダメージを受けた結果と推測出来る。磁性体に水分が混入して**透磁率**が変化したためである。インダクタ製品として致命的な問題である。

②重畠電流値測定

この試験が実施されていない。よって、真の電気性能実力は判断出来ない。

③振動試験結果について

3社で唯一**パナソニック製品**で異常が発生した。**クラック発生**が原因である。同社は各種の特許 (巻線接続方法他) を権利化しているが、実際の信頼性性能の点では問題が有ると言える。

